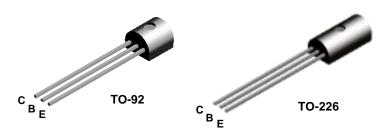
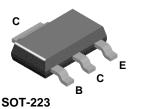


2N7051

2N7053

NZT7053





NPN Darlington Transistor

This device is designed for applications requiring extremely high gain at collector currents to 1.0 A and high breakdown voltage. Sourced from Process 06.

Absolute Maximum Ratings*

TA = 25°C unless otherwise noted

Symbol	Parameter	Value	Units
V_{CEO}	Collector-Emitter Voltage	100	V
V _{CBO}	Collector-Base Voltage	100	V
V _{EBO}	Emitter-Base Voltage	12	V
I _C	Collector Current - Continuous	1.5	A
T _J , T _{stg}	Operating and Storage Junction Temperature Range	-55 to +150	°C

^{*}These ratings are limiting values above which the serviceability of any semiconductor device may be impaired.

- NOTES:

 1) These ratings are based on a maximum junction temperature of 150 degrees C.

 2) These are steady state limits. The factory should be consulted on applications involving pulsed or low duty cycle operations.

Thermal Characteristics

TA = 25°C unless otherwise noted

Symbol	Characteristic	Max		Units	
		2N7051	2N7053	*NZT7053	
P _D	Total Device Dissipation	625	1,000	1,000	mW
	Derate above 25°C	5.0	8.0	8.0	mW/°C
$R_{\theta JC}$	Thermal Resistance, Junction to Case	83.3	50		°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	200	125	125	°C/W

^{*}Device mounted on FR-4 PCB 36 mm X 18 mm X 1.5 mm; mounting pad for the collector lead min. 6 cm².

NPN Darlington Transistor

(continued)

		4 . 4.
LIACTUA	al ('hara	ATAPICTIA:
Electic	ai Gilai a	cteristics

TA = 25°C unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Max	Units
OFF CHAP	RACTERISTICS				
$V_{(BR)CEO}$	Collector-Emitter Breakdown Voltage*	$I_C = 1.0 \text{ mA}, I_B = 0$	100		V
$V_{(BR)CBO}$	Collector-Base Breakdown Voltage	$I_C = 100 \mu A, I_E = 0$	100		V
$V_{(BR)EBO}$	Emitter-Base Breakdown Voltage	$I_E = 1.0 \text{ mA}, I_C = 0$	12		V
I _{CBO}	Collector-Cutoff Current	$V_{CB} = 80 \text{ V}, I_{E} = 0$		0.1	μΑ
I _{CES}	Collector-Cutoff Current	$V_{CE} = 80 \text{ V}, I_{E} = 0$		0.2	μΑ
I _{EBO}	Emitter-Cutoff Current	$V_{EB} = 7.0 \text{ V}, I_{C} = 0$		0.1	μΑ

ON CHARACTERISTICS*

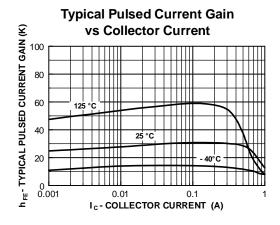
h _{FE}	DC Current Gain	$I_C = 100 \text{ mA}, V_{CE} = 5.0 \text{ V}$	10,000		
		$I_C = 1.0 \text{ A}, V_{CE} = 5.0 \text{ V}$	1,000	20,000	
V _{CE(sat)}	Collector-Emitter Saturation Voltage	$I_C = 100 \text{ mA}, I_B = 0.1 \text{ mA}$		1.5	V
V _{BE(on)}	Base-Emitter On Voltage	$I_C = 100 \text{ mA}, V_{BE} = 5.0 \text{ V}$		2.0	V

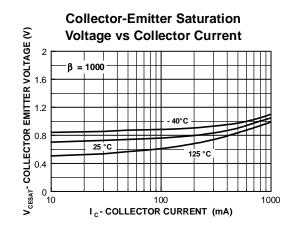
SMALL SIGNAL CHARACTERISTICS

F _T	Transition Frequency	$I_C = 100 \text{ mA}, V_{CE} = 5.0 \text{ V}$	200		MHz
C _{cb}	Collector-Base Capacitance	V _{CB} = 10 V,f= 1.0 MHz 2N7053		8.0	pF
h _{fe}	Small-Signal Current Gain	$V_{CE} = 5.0 \text{ V}, I_{C} = 100 \text{ mA},$ f = 20 MHz	10	100	

^{*}Pulse Test: Pulse Width \leq 300 μ s, Duty Cycle \leq 1.0%

Typical Characteristics

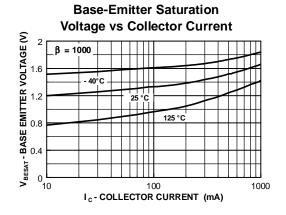


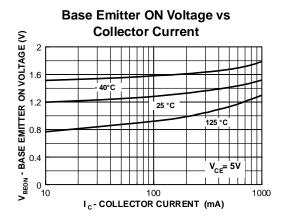


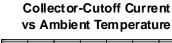
NPN Darlington Transistor

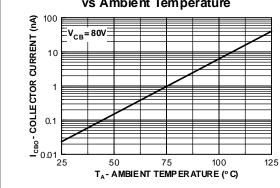
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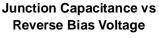
Typical Characteristics (continued)

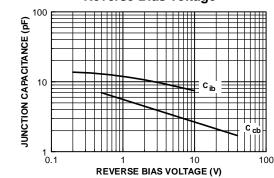




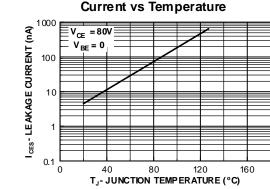




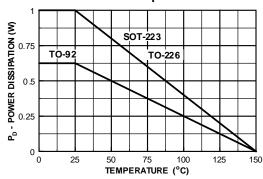




Typical Collector-Emitter Leakage Current vs Temperature



Power Dissipation vs Ambient Temperature



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PRODUCT STATUS DEFINITIONS

Definition of Terms

Datasheet Identification	Product Status	Definition
Advance Information	Formative or In Design	This datasheet contains the design specifications for product development. Specifications may change in any manner without notice.
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No Identification Needed	Full Production	This datasheet contains final specifications. Fairchild Semiconductor reserves the right to make changes at any time without notice in order to improve design.
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